Refine Search

Search Results -

Term	Documents
(13 AND 15).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	2
(L15 AND L13).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	2

Database:
```
US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins
```

Search: L26

[Refine Search]

[Recall Text] [Clear] [Interrupt]

Search History

DATE: Thursday, February 03, 2005 Printable Copy Create Case

Set Name side by side	Query	Hit Count	Set Name result set
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L26	L15 and l13	2	L26
L25	L15 and l12	21	L25
L24	L15 and l11	4	L24
L23	L15 and l10	55	L23
L22	L15 and l9	30	L22
L21	L15 and l8	48	L21
L20	L15 and l7	7	L20
L19	L15 and l6	7	L19
L18	L15 and l5	128	L18
L17	L15 and l4	2	L17
L16	L15 and l3	128	L16
L15	L14 and l2	989	L15

h   e   b   b   cg   b   e   e   ch

L14	(time) near4 (division$5 or multiplex$4)	108023	L14

DB=PGPB,USPT; PLUR=YES; OP=OR

L13	(370/238)[CCLS]	447	L13
L12	(370/230-240)[CCLS]	3725	L12
L11	(710/117,312)[CCLS]	210	L11
L10	(710/300-317)[CCLS]	8047	L10
L9	(711/130-153)![CCLS]	6712	L9
L8	(711/119-173)![CCLS]	14734	L8
L7	(712/13,29)![CCLS]	264	L7
L6	(712/13,29)[CCLS]	264	L6
L5	(712/2-300)[CCLS]	10687	L5
L4	(709/215,241)![CCLS]	439	L4
L3	(709/213-253)![CCLS]	27678	L3

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

L2	(common or shar$6) near4 (memor$4 or register$1 or stor$6 or stack$1) and (bridge$1) and rout$3	5413	L2
L1	(common or shar$6) near4 (memor$4 or register$1 or stor$6 or stack$1) near15 (bridge$1) near15 rout$3	47	L1

END OF SEARCH HISTORY

h   e b   b cg b   e e ch
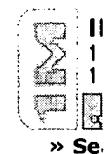
Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Se.

Help   FAQ   Terms   IEEE Peer Review

Quick Links

Welcome to IEEE Xplore

O- Home
O- What Can
   I Access?
O- Log-out

Tables of Contents

O- Journals
   & Magazines
O- Conference
   Proceedings
O- Standards

Search

O- By Author
O- Basic
O- Advanced
O- CrossRef

Member Services

O- Join IEEE
O- Establish IEEE
   Web Account
O- Access the
   IEEE Member
   Digital Library

IEEE Enterprise

O- Access the
   IEEE Enterprise
   File Cabinet

🖳 Print Format

Your search matched **3** of **1123491** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or enterii
new one in the text box.

(share or shared or sharing or shares or common) an   Search

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

---

1 **Switch fabric design and performance evaluation: metrics and pitfal**
Kavipurapu, G.N.; Nourani, M.;
Circuits and Systems, 2002. MWSCAS-2002. The 2002 45th Midwest Symposi
on , Volume: 2 , 4-7 Aug. 2002
Pages:II-123 - II-126 vol.2

[Abstract]   [PDF Full-Text (431 KB)]   **IEEE CNF**

---

2 **A measurement-analytic approach for QoS estimation in a network based on the dominant time scale**
Do Young Eun; Shroff, N.B.;
Networking, IEEE/ACM Transactions on , Volume: 11 , Issue: 2 , April 2003
Pages:222 - 235

[Abstract]   [PDF Full-Text (880 KB)]   **IEEE JNL**

---

3 **LIGHTNING-a WDM based distributed shared memory clustering tes network and physical layer**
Dagenais, M.;
Lasers and Electro-Optics Society Annual Meeting, 1995. 8th Annual Meeting
Conference Proceedings, Volume 1., IEEE , Volume: 1 , 30-31 Oct. 1995
Pages:195 - 197 vol.1

[Abstract]   [PDF Full-Text (124 KB)]   **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

h   eee   e eee   g e ch e ch e   e   c e   e   e c   e